

Notice of References Cited

Application/Control No.

09/678,255

Applicant(s)/Patent Under

Reexamination

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Examiner

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Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	O	EP-0456202 A2	11-1991	Europe	Kinney	G01N 21/53
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,	W	Edmund Industrial Optics, The Importance of Cleaning Optics, http://www.edmundoptics.co...upport/DisplayArticle.cfm?articleid=265
	X	NASA Practice No. PD-ED-1233, Contamination Control Program

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.